

# A O 3434 30V N-Channel MOSFET

## **General Description**

The AO3434 uses advanced trench technology to provide excellent  $R_{\text{DS}(\text{ON})}$  and low gate charge. This device is suitable for use as a load switch or in PWM applications. It is ESD protected.

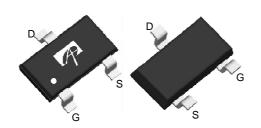
## **Product Summary**

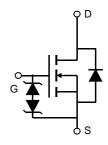
$$\begin{split} &V_{DS}\left(V\right) = 30V \\ &I_{D} = 4.2A & (V_{GS} = 10V) \\ &R_{DS(ON)} < 52m\Omega & (V_{GS} = 10V) \\ &R_{DS(ON)} < 75m\Omega & (V_{GS} = 4.5V) \end{split}$$

**ESD** protected



# SOT23 Top View Bottom View





# Absolute Maximum Ratings T<sub>A</sub>=25℃ unless otherwise noted

	Maximum		ximum		
Parameter		Symbol	10 sec	Steady-State	Units
Drain-Source Voltage		$V_{DS}$	30		V
Gate-Source Voltage		$V_{GS}$	±20		V
Continuous Drain	T <sub>A</sub> =25℃		4.2	3.5	
Current A,F	T <sub>A</sub> =70℃	I <sub>D</sub>	3.3	2.8	Α
Pulsed Drain Current <sup>B</sup>		I <sub>DM</sub>	30		
	T <sub>A</sub> =25℃	$-P_D$	1.4	1.0	W
Power Dissipation	T <sub>A</sub> =70℃	L D	0.9	0.64	VV
Junction and Storage Temperature Range		$T_J$ , $T_{STG}$	-55 to 150		${\mathfrak C}$

Thermal Characteristics							
Parameter		Symbol Typ		Max	Units		
Maximum Junction-to-Ambient A	t ≤ 10s	D	70	90	C/W		
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	$R_{\theta JA}$	100	125	C\M		
Maximum Junction-to-Lead <sup>C</sup>	Steady-State	$R_{\theta JL}$	63	80	℃/W		



#### Electrical Characteristics (T<sub>J</sub>=25℃ unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS}$ =30V, $V_{GS}$ =0V				1	μА
			T <sub>J</sub> =55℃			5	μπ
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ = ±16V				10	uA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=250\mu A$		1	1.32	1.8	V
	Static Drain-Source On-Resistance	$V_{GS}$ =10V, $I_D$ =4.2A			43	52	mΩ
$R_{DS(ON)}$			T <sub>J</sub> =125℃		58	74	
		$V_{GS}$ =4.5V, $I_D$ =2A			59	75	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS}$ =5V, $I_{D}$ =4.2A		8.5		S	
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V		0.77	1	V	
Is	Maximum Body-Diode Continuous Current					1.8	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance				269	340	pF
C <sub>oss</sub>	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =15V, f=		65		pF	
$C_{rss}$	Reverse Transfer Capacitance			41		pF	
$R_g$	Gate resistance	$V_{GS}$ =0V, $V_{DS}$ =0V, f=1		1	1.5	Ω	
SWITCHI	NG PARAMETERS						
Q <sub>g</sub> (10V)	Total Gate Charge	-V <sub>GS</sub> =10V, V <sub>DS</sub> =15V, I <sub>D</sub> =4.2A			5.7	7.2	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge				3		nC
$Q_{gs}$	Gate Source Charge				1.37		nC
$Q_{gd}$	Gate Drain Charge				0.65		nC
t <sub>D(on)</sub>	Turn-On DelayTime				2.6	3.8	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $R_L$ =3.6 $\Omega$ , $R_{GEN}$ =3 $\Omega$			5.5	8	ns
t <sub>D(off)</sub>	Turn-Off DelayTime				15.2	23	ns
t <sub>f</sub>	Turn-Off Fall Time				3.7	5.5	ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =4.2A, dI/dt=100A/μs			15.5	21	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	I <sub>F</sub> =4.2A, dI/dt=100A/μs			7.1		nC

A: The value of R <sub>0JA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T <sub>A</sub>=25° C. The value in any given application depends on the user's specific board design.

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B: Repetitive rating, pulse width limited by junction temperature.

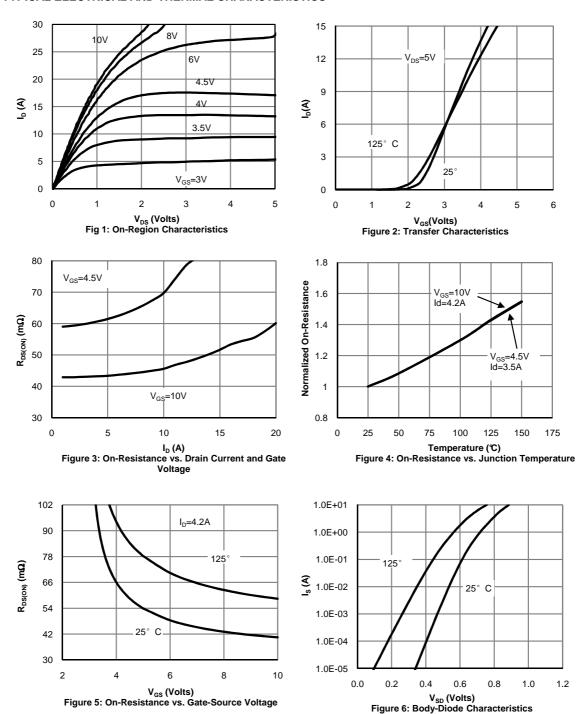
C. The R  $_{\theta JA}$  is the sum of the thermal impedence from junction to lead R  $_{\theta JL}$  and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300 µs pulses, duty cycle 0.5% max.

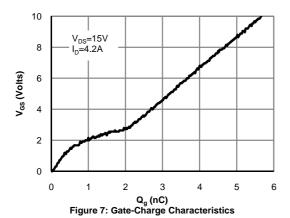
E. These tests are performed with the device mounted on 1 in <sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25° C. The SOA curve provides a single pulse rating.

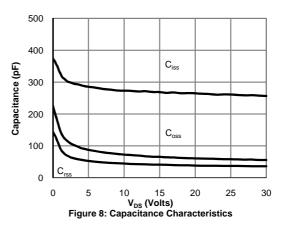
F.The current rating is based on the t≤10s thermal resistance rating.

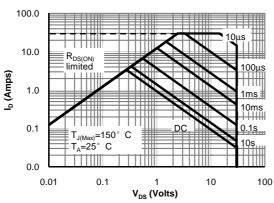
#### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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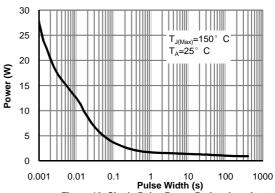


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

